

**Search Notes**

Application/Control No.

10/755,019

Examiner

David Nhu

Applicant(s)/Patent under  
Reexamination

NAKAI ET AL.

Art Unit

2818

**SEARCHED**

Class	Subclass	Date	Examiner
257	288	6/9/2005	
	289, 290		
	291, 292		
	293, 294		
	257, 258		
	461, 462		
	59		
	82		
	98		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
SEARCHED IN EAST	6/9/2005	DN
SEARCHED IN EAST	2/23/2006	DN